## Notice of References Cited

	<i></i>	
Application/Control No.	Applicant(s)/Pater	nt Under
09/592,791	Reexamination WATANABE, KEI	TA
Examiner	Art Unit	
Devona F. Faulk	2644	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,844,484	12-1998	Fujiuchi et al.	340/572.1
	В	US-3,858,389	01-1975	Isuruishi, Yuki	368/245
	С	US-		, < 1 to - Pro- to	
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	H	US-	,		
	_	US-			
	J	US-	4		
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>&gt;</b>	
	w	,
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.